## **Electronic Supplementary Information**

for

# Efficient photoactivated hydrogen evolution promoted by $Cu_xO$ -gCN-TiO<sub>2</sub>-Au (x=1,2) nanoarchitectures

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## **Table of Contents**

	Page
§ S-1. Experimental	S3
§ S-1.1. Chemico-physical characterization	S3
§ S-1.2. Functional tests	S3
§ S-2. Additional characterization results	S6
§ S-2.1. Characterization of the obtained systems	S6
§ S-2.2. Functional tests and related analyses	S12
§ S-3. References	S27

#### § S-1. Experimental

#### § S-1.1. Chemico-physical characterization

X-ray diffraction (XRD) was performed in glancing incidence mode ( $\theta_i = 1.0^\circ$ ) on a Bruker AXS D8 Advance Plus diffractometer, equipped with a Göbel mirror and a CuK $\alpha$  X-ray source ( $\lambda = 1.54051$ Å) powered at 40 kV and 40 mA. The analyses were carried out at the PanLab facility (Department of Chemical Sciences, Padova University) founded by the MIUR Dipartimento di Eccellenza grant "NExuS".

Copper Auger parameter was calculated as the sum of Cu  $2p_{3/2}$  BE and the Cu *LMM* Auger peak kinetic energy (KE):<sup>1, 2</sup>

$$\alpha = BE(Cu 2p_{3/2}) + KE(Cu LMM)$$
(S1)

Elemental atomic percentage (at.%) values were computed by peak area integration, using sensitivity factors provided by Specs.

Cross-sectional samples for transmission electron microscopy (TEM) analyses were prepared using a FEI Versa3D focus ion beam-scanning electron microscope (FIB-SEM). The final polishing of TEM specimens was performed using a Ga ion beam, under conditions enabling to minimize detrimental material alterations (energy = 2 kV; beam current  $\approx$  25 pA).

#### § S-1.2. Functional tests

Current density values were obtained by dividing the measured currents for the exposed geometric area ( $\approx 1.20 \text{ cm}^2$ ). In fact, for materials as the present ones, BET measurements of the real active area and a reliable evaluation of electrochemical active surface area (ECSA) are not possible, as already reported.<sup>3-5</sup>

The potential of the Hg/HgO (MMO) reference electrode was periodically recalibrated after tests and no significant variation with respect to RHE was ever detected, ensuring thus a full reproducibility of the obtained results.

Linear sweep voltammetry (LSV) curves were collected at a scan rate of 5 mV/s. The potential values *vs.* MMO ( $E_{MMO}$ ) were converted into the corresponding ones on the reversible hydrogen electrode (RHE) scale ( $E_{RHE}$ ) using the relation:

$$E_{RHE}(V) = E_{MMO}(V) + 0.0592 \times pH + 0.075$$
 (S2)

Applied bias photon-to-current efficiency (ABPE) (%) curves were obtained through the equation:<sup>6</sup>

ABPE (%) = 
$$(|j \times E| / P) \times 100$$
 (S3)

were j (mA/cm<sup>2</sup>) is the photocurrent density at the potential E (V vs. RHE), and P is the incident light intensity (100 mW/cm<sup>2</sup>). In this work, all the reported j values (including those in Tables S1-S2), apart from the case of Fig. 9 that displays the current densities as such, are calculated as the difference between the values recorded under illumination and in the dark.

For all the performed photoelectrochemical tests, a neutral white LED (220 lm, 700 mA) has been employed (Fig. S1). In a typical experiment, the sample was illuminated from the front side with the maximum light intensity (corresponding to an input current of 700 mA) at a distance of 10 cm from the specimen surface. In order to obtain quantitative results, the light source intensity was periodically re-calibrated prior to measurements.



Fig. S1. Spectrum of the light source employed for photoelectrochemical tests. The light intensity in the Y axis is scaled to the maximum at  $\lambda \approx 560$  nm.

Electrochemical impedance spectroscopy (EIS) experiments were carried out between 1 and 10<sup>5</sup> Hz with a 10 mV perturbation. Mott-Schottky plots were obtained at 1.0 kHz by recording EIS

spectra between 0.0 and 0.6 V vs. RHE, with 0.05 V steps. The flatband potential ( $V_{FB}$ ) was measured by fitting the linear part of  $1/C_{SC}^2$  and finding the intercept with the potential axis, using the equation:<sup>7-10</sup>

$$\frac{1}{C_{sc}^2} = \frac{2}{\varepsilon_0 \varepsilon_r e N_A} \left( V - V_{FB} - \frac{k_B T}{e} \right)$$
(S4)

where  $C_{SC}$  is the semiconductor capacitance (the contribution of the double layer capacitance,  $1/C_{H}^{2}$ , is considered negligible),  $\varepsilon_{0}$  and  $\varepsilon_{r}$  are the free space permittivity and the material relative permittivity, e is the electron charge (C),  $N_{A}$  is the majority carrier density, V is the applied bias, and  $k_{B}$  is the Boltzmann constant. The capacitance  $C_{SC}$  was calculated at 1054 Hz by using the usual formula:

$$Z'' = -\frac{i}{C_{sc} \cdot \omega}$$
(S5)

where Z" is the complex component of the measured impedance. The Fermi level energy ( $E_F$ ) was assumed to be coincident with  $V_{FB}$ , and was used to construct the diagram reported in Fig. 4e. The  $E_F$  value in Fig. 4e corresponds to  $V_{FB}$  of sample Cu<sub>x</sub>O-gCN-TiO<sub>2</sub>-Au (purple line in Fig. 4d and S11).

Chronoamperometry (CA) measurements were performed by recording the photocurrent as a function of time at 0.0 V vs. RHE.

Preliminary photoreforming experiments for H<sub>2</sub> generation were performed from 1:1 waterethanol mixtures, using a previously described reactor<sup>11</sup> stabilized at 25°C and purged for  $\approx$  30 min with an Ar flow (rate = 15 mL/min) prior to measurements. Irradiation was carried out using a solar simulator (Lot-Oriel) equipped with a 150 W Xe lamp and an atmospheric edge filter. The on-line detection of the evolved hydrogen was carried out using an Agilent 7890A gas chromatographer. A Carboxen 1010 PLOT column (Supelco) connected to a thermal conductivity detector was adopted for H<sub>2</sub> quantification, using Ar as carrier. Based on the sample geometrical area (see above), H<sub>2</sub> production rates were expressed as mmol h<sup>-1</sup> m<sup>-2</sup>.<sup>11, 12</sup> Prof. Paolo Fornasiero and Dr. Valentina Gombac (Department of Chemical and Pharmaceutical Sciences, Trieste University and INSTM, Italy) are gratefully acknowledged for such tests.

#### § S-2. Additional characterization results

### § S-2.1. Characterization of the obtained systems

FE-SEM and EDXS analyses of sample  $Cu_xO$ -gCN (Fig. S2a-b and S3) clearly displayed the formation of a porous gCN overlayer. The presence of  $Cu_xO$  nanowires was still evident, despite in an apparently lower concentration in comparison to the pristine  $Cu_xO$  (compare Fig. 1b-e in the main paper text). These variations in the system morphology can be ascribed to a partial coverage and embedding of copper oxide nanowires into the deposited gCN matrix, which is maintained even after  $TiO_2$  and Au introduction by RF-Sputtering (see Fig. S2c). The inherent porosity of the starting copper foam and the adopted synthetic strategy, with particular regard to the RF-Sputtering infiltration capability, favor an intimate intermixing of the single system components, beneficially affecting the ultimate functional performances (see the main paper text).



**Fig. S2.** Representative FE-SEM micrographs for  $Cu_xO$ -gCN and  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au photoelectrocatalysts.



**Fig. S3.** EDXS O, Cu, C, and N elemental maps for sample  $Cu_xO$ -gCN, recorded on the electron image displayed in the top left corner.



**Fig. S4.** XRD patterns for the target specimens. The reference peak positions for Cu,<sup>13</sup> Cu<sub>2</sub>O,<sup>14</sup> and CuO<sup>15</sup> are marked by squares, triangles, and circles, respectively.



**Fig. S5.** XPS survey spectra for  $Cu_xO$ -gCN,  $Cu_xO$ -gCN-TiO<sub>2</sub> and  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au. For both composite systems, the measured N/Cu atomic percentage ratio corresponds to 0.030.



Fig. S6. Au 4f (a), Ti 2p (b) and Cu LMM Auger (c) signals for the indicated specimens.



Fig. S7. Atomic resolution STEM ADF images showing lattice fringes in areas close to Au nanoparticles, as indicated by the dashed red circles. The lattice fringe distances are consistent with those of  $TiO_2$ .



**Fig. S8.** An electron diffraction pattern acquired from gCN area in the target specimens. The diffused rings in the pattern show that graphitic caron nitride is amorphous.

#### § S-2.2. Functional tests and related analyses



**Fig. S9.** Linear sweep voltammetry recorded for sample  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au collected in the dark and under illumination.



**Fig. S10.** Photocurrent *vs.* bias for four replicas of sample  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au, the best performing one. As can be observed, no appreciable current density variations were detected, demonstrating the repeatability of the results.



**Fig. S11.** Mott-Schottky plots at 1 KHz as a function of the applied bias for the investigated electrocatalysts. Experimental and fitting curves correspond to dashed and continuous lines, respectively.



**Fig. S12.** Tafel plot for the target samples obtained from the LSV curves reported in Fig. 4a. Dashed and continuous lines indicate experimental and fitting curves, respectively.

Sample	Electrolyte	j₀ (mA/cm²)	ABPE <sub>max</sub> (%)	E <sub>Wmax</sub> (V <sub>RHE</sub> )	Tafel slope (mV/dec)
Cu <sub>x</sub> O	KHCO₃ 0.5 M	-2.68	1	0.19	-227
Cu <sub>x</sub> O-gCN		-3.86	2.17	0.20	-207
Cu <sub>x</sub> O-gCN-TiO <sub>2</sub>		-4.58	2.42	0.19	-177
Cu <sub>x</sub> O-gCN-TiO <sub>2-</sub> Au		-5.73	2.92	0.19	-160

**Table S1.** Hydrogen evolution reaction (HER) performances for the fabricated specimens.  $j_0$  corresponds to the photocurrent density measured at 0.0 V vs. RHE. ABPE<sub>max</sub> values correspond to the maximum efficiency in each of the applied bias photon-to-current efficiency (ABPE) curves in Fig. 4c, normalized with respect to bare Cu<sub>x</sub>O. E<sub>Wmax</sub> is the corresponding potential value vs. RHE.

Material	Electrolyte	j₀ (mA/cm²)	ABPE <sub>max</sub> (%)	E <sub>Wmax</sub> (V <sub>RHE</sub> )	Tafel slope (mV/dec)	Ref.
Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 1.0 M + HCOOH 0.5 M	≈ -2.0	n.a.	n.a.	n.a.	16
Cu <sub>2</sub> O	H <sub>2</sub> SO <sub>4</sub> 0.025 M	≈ 0	n.a.	n.a.	n.a.	17
Cu <sub>2</sub> O		≈ -0.28 <sup>a</sup>	n.a.	n.a.	n.a.	18
Cu <sub>2</sub> O		≈ -0.02 <sup>b</sup>	n.a.	n.a.	n.a.	19
Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 0.2 M	≈ -0.09	n.a.	n.a.	n.a.	20
Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 0.5 M	≈ -0.14	0.12	0.05	n.a.	21
Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 0.5 M at <i>pH</i> = 4.9	≈ -0.51	0.02	0.18	n.a.	6
Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 1.0 M	≈ -2.23 <sup>c</sup>	n.a.	n.a.	n.a.	22
Dual Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 0.5 M + KH <sub>2</sub> PO <sub>4</sub> 0.1 M	≈ -7.0	1.9	0.45	n.a.	23
Pt-Cu <sub>2</sub> O <sup>d</sup>	Na <sub>2</sub> SO <sub>4</sub> 0.1 M	≈ -1.1	n.a.	n.a.	n.a.	24
CuO	H <sub>2</sub> SO <sub>4</sub> 0.025 M	≈ 0	n.a.	n.a.	n.a.	17
CuO	Na <sub>2</sub> SO <sub>4</sub> 1.0 M + HCOOH 0.5 M	≈ -1.2	n.a.	n.a.	n.a.	16

Material	Electrolyte	j₀ (mA/cm²)	ABPE <sub>max</sub> (%)	E <sub>Wmax</sub> (V <sub>RHE</sub> )	Tafel slope (mV/dec)	Ref.
CuO		≈ -0.46	0.08	0.24	n.a.	10
CuO <sup>e</sup>		≈ -0.80	n.a.	n.a.	n.a.	25
CuO		≈ -0.35 <sup>a</sup>	n.a.	n.a.	n.a.	18
CuO <sup>f</sup>		≈ -1.2	n.a.	n.a.	n.a.	9
CuO	Na <sub>2</sub> SO <sub>4</sub> 0.1 M	≈ -0.45	n.a.	n.a.	n.a.	26
CuO		≈ -2.18	n.a.	n.a.	n.a.	27
CuO		≈ -0.25 <sup>b</sup>	n.a.	n.a.	n.a.	19
CuO		≈ -0.76	n.a.	n.a.	n.a.	28
CuO	Na <sub>2</sub> SO <sub>4</sub> 0.2 M	≈ -0.90	n.a.	n.a.	n.a.	20
CuO		≈ -1.28	0.43	0.10	n.a.	21
CuO	Na <sub>2</sub> SO <sub>4</sub> 0.5 M	-0.92	n.a.	n.a.	n.a.	29
Pt-CuO	Na <sub>2</sub> SO <sub>4</sub> 1.0 M	≈ -1.15	n.a.	n.a.	n.a.	30
CuO-Cu <sub>2</sub> O <sup>g</sup>	Na <sub>2</sub> SO <sub>4</sub> 1.0 M + HCOOH 0.5 M	≈ -4.5	n.a.	n.a.	n.a.	16

Material	Electrolyte	j₀ (mA/cm²)	ABPE <sub>max</sub> (%)	E <sub>Wmax</sub> (V <sub>RHE</sub> )	Tafel slope (mV/dec)	Ref.
CuO-Cu <sub>2</sub> O	Na <sub>2</sub> SO <sub>4</sub> 0.1 M	≈ -0.62	n.a.	n.a.	n.a.	31
CuO-Cu <sub>2</sub> O <sup>g</sup>	Na <sub>2</sub> SO <sub>4</sub> 1.0 M	≈ -0.14	n.a.	n.a.	n.a.	32
CuO/Cu <sub>2</sub> O <sup>h</sup>	Na <sub>2</sub> SO <sub>4</sub> 0.2 M	≈ -1.01	n.a.	n.a.	n.a.	20
Cu <sub>2</sub> O/CuO	Na <sub>2</sub> SO <sub>4</sub> 0.5 M	≈ -2.6	0.55	0.05	n.a.	21
Cu/Cu <sub>2</sub> O/CuO	Na <sub>2</sub> SO <sub>4</sub> 50 mM buffered at $pH = 6.82$	-1.54	n.a.	n.a.	n.a.	33
Cu/Cu <sub>2</sub> O/Cu(OH) <sub>2</sub>		-1.28	n.a.	n.a.	n.a.	
CuO/NiO	Na <sub>2</sub> SO <sub>4</sub> 0.5 M	-1.02	n.a.	n.a.	n.a.	29
Cu <sub>2</sub> O/SnO <sub>2</sub> /RuO <sub>2</sub>	Na <sub>2</sub> SO <sub>4</sub> 0.5 M + KH <sub>2</sub> PO <sub>4</sub> 0.1 M	≈ -4.30	n.a.	n.a.	n.a.	34
(CuO/CuO:Al)/ZnO:Al/TiO <sub>2</sub> /Au–Pd		≈ -4.58	n.a.	n.a.	n.a.	35
TiO <sub>2</sub> /CuO	Na <sub>2</sub> SO <sub>4</sub> 0.1 M	≈ -0.53 <sup>b</sup>	n.a.	n.a.	n.a.	19
Cu/TiO <sub>2</sub>	KOH 1.0 M	≈ -0.01	n.a.	n.a.	n.a.	36
Cu <sub>2</sub> O/TiO <sub>2</sub>	Na <sub>2</sub> SO <sub>4</sub> 0.5 M at <i>pH</i> = 4.9	≈ -1.15	0.12	0.22	n.a.	6
Cu <sub>2</sub> O/TiO <sub>2</sub> /NiFe	Na <sub>2</sub> SO <sub>4</sub> 0.5 M at <i>pH</i> = 4.9	≈ -2.67	0.27	0.18	n.a.	6

Material	Electrolyte	j <sub>0</sub> (mA/cm²)	ABPE <sub>max</sub> (%)	E <sub>Wmax</sub> (V <sub>RHE</sub> )	Tafel slope (mV/dec)	Ref.
gCN/CuO	Na <sub>2</sub> SO <sub>4</sub> 0.1 M	≈ -0.65	0.12	0.24	n.a.	10
CuO/gCN		≈ -0.50 <sup>i</sup>	n.a.	n.a.	n.a.	37
gCN-CuO	Phosphate buffer ( <i>pH</i> = 7)	≈ -0.40 <sup>i</sup>	n.a.	n.a.	n.a.	38
Cul@gCN-CuO <sup>7</sup>		≈ -0.50 <sup>i</sup>	n.a.	n.a.	n.a.	38
CuO/gCN	Na <sub>2</sub> SO <sub>4</sub> 0.1 M	≈ 10 <sup>-4 c</sup>	n.a.	n.a.	-314	39
Pt-Cu <sub>2</sub> O/gCN <sup>d</sup>		≈ -1.7	n.a.	n.a.	n.a.	24
gCN/CuO		≈ -1.63	n.a.	n.a.	n.a.	28
gCN/C-CuO		≈ -2.37	n.a.	n.a.	n.a.	28
Cu <sub>2</sub> O/TiO <sub>2</sub> /rGO/NiFe <sup>m</sup>	Na <sub>2</sub> SO <sub>4</sub> 0.5 M at <i>pH</i> = 4.9	≈ -3.18	0.41	0.25	n.a.	6

**Table S2.** HER performances of selected (photo)electrocatalysts based on bare  $Cu_xO(x=1,2)$  and related composites.  $j_0$  is defined as in Table S1. *n.a.* = not available.  $^a @ \approx 0.04 V vs$ . RHE.  $^b @ \approx -0.20 V vs$ . RHE.  $^c @ \approx 0.24 V vs$ . RHE.  $^d Cu_2O$  foam.  $^e$  porous pyramids.  $^f$  film thickness = 150 nm.  $^g$  biphasic thin film.  $^h$  heterojunction structure.  $^i @ \approx 0.06 V vs$ . RHE.  $^l$  with a metallic Cu underlayer.  $^m$  rGO = reduced graphene oxide.



**Fig. S13.** Chronoamperometric (CA) traces for the investigated electrocatalysts, recorded at 0.0 V *vs.* RHE.



**Fig. S14.** LSV curves recorded on as-prepared samples (solid lines) and collected every 90 days for six months upon specimen storage under ambient conditions (dashed lines).



**Fig. S15.** XPS photopeaks for  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au before (solid line) and after storage under ambient conditions for six months, during which the specimen was subjected to photoelectrochemical tests every 90 days. The dotted line spectra reported herein have been obtained at the end of these repeated tests. In (d), shake-up satellites are denoted by \*.



**Fig. S16.** XPS atomic percentage (%) values for  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au before photoelectrochemical tests (pre EC, in blue), and after storage under ambient conditions for six months, during which each sample was subjected to photoelectrochemical tests every 90 days (post EC, in orange). The post EC data reported herein have been obtained at the end of these repeated tests.



**Fig. S17.** FE-SEM micrographs for  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au after storage under ambient conditions for six months, during which the sample was subjected to photoelectrochemical tests every 90 days.



**Fig. S18.** (a)  $H_2$  evolution rate and (b) integrated  $H_2$  production obtained by photoreforming of 1:1 water-ethanol solutions on a Cu<sub>x</sub>O-gCN-TiO<sub>2</sub>-Au sample under simulated solar illumination.

Preliminary tests on hydrogen photogeneration in the absence of any external bias were carried out by photoreforming of water-ethanol solutions on  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au, the best performing specimen in photoelectrochemical experiments (compare Fig. 4 in the main paper text and related comments). In the case of mixtures of water and oxygenated organic compounds (*e.g.* ethanol, glucose, glycerol... ), photoreforming takes place instead of the simple water splitting. The process involves the partial or complete oxidation of organics (depending on experimental conditions), such species being more easily oxidized than water.<sup>40, 41</sup> In the case of complete oxidation, the photoreforming process can be described by the following general reaction:

$$C_nH_mO_k + (2n - k) H_2O \rightarrow n CO_2 + (2n + m/2 - k) H_2$$
 (S6)

The bias-free  $H_2$  evolution performances of  $Cu_xO$ -gCN-TiO<sub>2</sub>-Au obtained in the present work were higher than those afforded by various homologous photocatalysts reported so far in previous studies:

- i) Cu<sub>2</sub>O-TiO<sub>2</sub>;<sup>42</sup>
- ii) gCN-TiO<sub>2</sub>;<sup>43-47</sup>
- iii) gCN-Cu<sub>2</sub>O;<sup>48</sup>

iv) gCN-CuO;<sup>49</sup>
 v) gCN-CuO-TiO<sub>2</sub>;<sup>50</sup>
 vi) gCN-Cu<sub>2</sub>O-TiO<sub>2</sub>;<sup>51</sup>
 vii) gCN-TiO<sub>2</sub>-Au;<sup>52</sup>
 viii) gCN-TiO<sub>2</sub>-Pt.<sup>53, 54</sup>

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